

10th International "Hiroshima" Symposium on the Development and
Application of Semiconductor Tracking Detectors, Xi'an, China

Contribution ID: 85

Type: POSTER

proton radiation damage test studies on Si MCZ detector

Saturday, 26 September 2015 19:37 (1 minute)

The displacement damage induced by high energy proton irradiation were measured with I_DLTs. The detector typical electronic parameters including I-V, C-V, and electric field profile influenced by proton radiation damage were tested and analyzed.

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Session Classification: After dinner POSTER session, with drinks: (All presenters are requested/encouraged to attend their posters; All participants are requested to participate the session, with drinks!)

Track Classification: Radiation damage, Environmental radiation monitoring